



Integrated Device Technology, Inc.
2975 Stender Way, Santa Clara, CA - 95054

PRODUCT/PROCESS CHANGE NOTICE (PCN)

PCN #: **I0206-04** DATE: June 14, 2002
 Product Affected: IDT79R3041
 Date Effective: September 14, 2002

MEANS OF DISTINGUISHING CHANGED DEVICES:
 Product Mark
 Back Mark
 Date Code Top mark will have the character "4"
 Other included in the die revision.

Contact: Bimla Paul
 Title: Quality Assurance Manager Attachment: Yes No
 Phone #: (408)-654-6419
 Fax #: (408)-492-8362 Samples: Available upon request.
 E-mail: bimla.paul@idt.com

DESCRIPTION AND PURPOSE OF CHANGE:

- | | |
|--------------------------------------------------------|---------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------|
| <input type="checkbox"/> Die Technology | To consolidate wafer fab production from Salinas, California (Fab 2) to Hillsboro, Oregon (Fab 4), IDT79R3041 will be transferred to IDT's wafer fab facility in Hillsboro, Oregon. There is no change in die technology. |
| <input type="checkbox"/> Wafer Fabrication Process | |
| <input type="checkbox"/> Assembly Process | |
| <input type="checkbox"/> Equipment | |
| <input type="checkbox"/> Material | |
| <input type="checkbox"/> Testing | |
| <input checked="" type="checkbox"/> Manufacturing Site | |
| <input type="checkbox"/> Data Sheet | |
| <input type="checkbox"/> Other | |

RELIABILITY/QUALIFICATION SUMMARY:

Qualification testing will verify that there is no change to the product reliability. Please see attachment for qualification detail.

CUSTOMER ACKNOWLEDGMENT OF RECEIPT:

IDT records indicate that you require written notification of this change. Please use the acknowledgement below or E-Mail to grant approval or request additional information. If IDT does not receive acknowledgement within 30 days of this notice it will be assumed that this change is acceptable.
 IDT reserves the right to ship either version manufactured after the process change effective date until the inventory on the earlier version has been depleted.

Customer: _____ **Approval for shipments prior to effective date.**
 Name/Date: _____ E-Mail Address: _____
 Title: _____ Phone# /Fax# : _____

CUSTOMER COMMENTS: _____

IDT ACKNOWLEDGMENT OF RECEIPT:

RECD. BY: _____ DATE: _____



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ATTACHMENT - PCN #: I0206-04

PCN Type: Fab Site Change

Data Sheet Change: None

Detail of Change: Transfer existing qualified product IDT79R3041 from Salinas, California Wafer Fab Facility (Fab 2) to Hillsboro, Oregon Wafer Fab Facility (Fab 4).

Part Number	Salinas Wafer Fab			Hillsboro Wafer Fab		
	Manufacturing Site	Wafer Size	Die Revision	Manufacturing Site	Wafer Size	Die Revision
IDT79R3041	Salinas, CA	6 inch	XG	Hillsboro, OR	8 inch	X4G

Note: There is no change in die technology.

Conversion schedule (Estimated)

Device IDT79R3041	Sample Availability Now	Production Shipments September 14, 2002
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ATTACHMENT - PCN #: I0206-04

Qualification Plan: QI02-01

Test Vehicle: IDT79R3041

Expected Completion Date: July 26, 2002

	Required Sample/#Fails	Lot #1
Operating Life Test (Dynamic) (1000 Hrs, @125 °C, Vcc = 5.5V)	77/0	
Bake & Ballshear Test @ 200°C / 4 ball bonds per device	5/0	
ESD Human Body Model	3/0	
ESD Charge Device Model	3/0	
Latch up	10/0	
Electrical Characterization	10	

Characterization Data:

Characterization data is available upon request.